





TEST REPORT

REPORT NO.: CTNT240429014



Product name: LED Facial Mask

Model No.: SR-M4

Applicant: Shenzhen Sunsred Technology Co., Ltd.

Test procedure: Entrustment Test

Shenzhen Zhongwei

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IEC 62471:2006 Photobiological safety of lamps and lamp systems

EN 62471:2008 Photobiological safety of lamps and lamp systems

Report Number. : CTNT240429014

Date of issue: Nov 19, 2024

Shenzhen Zhongwei Testing Technology Co., Ltd.

Room 1A106, 1/F., No.109, Lijia Road, Henggang, Henggang Street,

Name of Testing Laboratory

Longgang District, Shenzhen, Guangdong, China

preparing the Report...... Tel: 086-13662574496

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Longhua DistrictShenzhen, Guangdong, China

Manufacturer's name: Shenzhen Sunsred Technology Co., Ltd.

Longhua DistrictShenzhen, Guangdong, China

Test specification:

Standard.....: IEC 62471:2006

EN 62471:2008

Test procedure: Entrustment Test

Non-standard test method: N/A

Test Report Form No. IEC 62471B

Test Report Form(s) Originator: VDE Testing and Certification Institute

Master TRF.....: Dated 2018-08-16

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Test item description: LED Facial Mask			
Frade Mark: N/A			
Model/Type reference: SR-M4, SR-M1, SR-M2, SR-M3, SR-M5, SR-M6, SR-M7, SR-M8			
Test item particulars			
Information for safety use N/A			
Responsible Testing Laboratory (as applicable), testing procedure and testing location(s):			
Laboratory Name	Shen	zhen Zhongwei Te	sting Technology Co., Ltd.
Testing location/ address::			g C, No.108, Lijia Road, Henggang t, Shenzhen, Guangdong, China
Tested by(Test Engineer)::	Olive	r Long	Oliver long
Reviewed By(Supervisor):	Airan	Lu	Arman Low
Approved by(Chief Engineer):	Flight Lee		₹CTNT €
- Photo document, - Test data graph			
Summary of testing:			
Tests performed (name of test and test clause):		Testing location:	
Determination of the result includes consideration of measurement uncertainty from the test equipment and methods. According to the test of IEC 62471:2006 According to the test of EN 62471:2008 Photobiological safety of lamps and lamp systems. The unit group classification of B+NiR mode is Risk Group 1 (Low-Risk); The unit group classification of R+NiR mode is Except Group;		Shenzhen Zhongwei Testing Technology Co., Ltd. Room 114, 2/F., Building C, No.108, Lijia Road, Henggang Street, Longgang District, Shenzhen, Guangdong, China Tel: 086-755-28680489 E-mail: admin@ctnt-cert.com Web: www.ctnt-cert.com	
The unit group classification of Y+NiR patter Except Group; All things considered, This product is Risk Group 1 (Low-Risk)	n is	A Section of the sect	